

IN THE CLAIMS:

Page 6, before claim 1, insert the following new paragraph:

(New) What is claimed is:

This following list of claims will replace all prior versions of claims in the above-identified application:

List of Claims

Claim 1. (Original) A method of calibrating a gauge for measuring film weight, the gauge including a probe, the method comprising the steps of:

- (a) determining a universal calibration constant for a material from a first standard having a known capacitance and weight;
- (b) measuring the weight of a second standard of known weight;
- (c) calculating the difference between the measured weight and the known weight of the second standard to obtain a calibration variable; and
 - either (c) resetting the calibration variable so that the measured weight of the second standard corresponds to its known weight, thereby recalibrating the gauge, or (d) cleaning the tip of the probe.

Claim 2. (Currently Amended) [[A]] The method according to claim 1, in which the second standard is a laminate.

Claim 3. (Currently Amended) [[A]] The method according to claim 1 ~~or claim 2~~ in which the second standard includes a layer of polyethylene terephthalate.

Claim 4. (Currently Amended) [[A]] The method according to ~~any one of claims 1 to 3~~ claim 1, further comprising the steps of:

- (e) placing a capacitance of known value in series with the gauge; and
- (f) measuring the capacitance of a circuit formed by the gauge and known capacitor to obtain an indication of the degree of deterioration of the probe tip.

Claim 5. (New) The method according to claim 2 in which the second standard includes a layer of polyethylene terephthalate.

Claim 6. (New) The method according to claim 2, further comprising the steps of:

- (e) placing a capacitance of known value in series with the gauge; and
- (f) measuring the capacitance of a circuit formed by the gauge and known capacitor to obtain an indication of the degree of deterioration of the probe tip.

Claim 7. (New) The method according to claim 3, further comprising the steps of:

- (e) placing a capacitance of known value in series with the gauge; and
- (f) measuring the capacitance of a circuit formed by the gauge and known capacitor to obtain an indication of the degree of deterioration of the probe tip.